Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination		
10/772,292	LEE ET AL.		
Examiner	Art Unit	_	
SIMON D. NGUYEN	2618		

SEARCHED				
Class	Subclass	Date	Examiner	
455	232.1	6/29/2006	SDN	
-	234.1			
	234.2			
	239.1-			
	241.1			
	245.1-			
	253.2			
	63.1			
375	317-319			
	345			

INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	

SEARCH NOTES (INCLUDING SEARCH STRATEGY)			
	DATE	EXMR	
EAST	6/29/2006	SDN	